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The Silicon Vertex Detector of the Belle II Experiment

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Outline

- SuperKEKB and Belle II
- Belle II Silicon Vertex Detector
- Operation & performance
- Beam background, radiation effects & future perspective
- Long Shutdown 1 (LS1) activities with new VXD installation
- Summary and conclusions

SuperKEKB and Belle II

• SuperKEKB: dedicated accelerator for Belle II

- \circ e⁺e⁻ collisions at Y(4S) resonance (10.58 GeV)
- Target integrated luminosity: 50 ab⁻¹
- Target instantaneous luminosity: ~6×10³⁵ cm⁻² s⁻¹
- World record peak luminosity: 4.7×10³⁴ cm⁻² s⁻¹

• Belle II detector

- New physics search at the luminosity frontier
- So far 424 fb⁻¹ data accumulated since March 2019
- Clean environment; well defined initial state
- Excellent vertexing and flavour tagging performance
- Efficient neutral reconstruction capability



Belle II Vertex Detector (VXD)

- Layers 1,2: Pixel Detector (PXD)
 - DEPFET pixel sensors
 - Innermost layer 1.4 cm radially from interaction point

(See Laci Andricek's talk on PXD)

- Layers 3-6: Silicon Vertex Detector (SVD)
 - Double sided silicon strip detectors

• Main features of SVD

- Standalone tracking for low momentum tracks
- Extrapolate tracks to PXD
- Precise vertexing of K_s
- Particle identification using dE/dx

• VXD Requirements:

SVD

- Better vertex resolution than Belle
- Operate in high bkg environment
 - Hit rate ~5 MHz/cm² @ layer-3

 ρ^{\dagger}

■ TID ~0.35 Mrad/yr @ layer-3

TIPP2023

PXD

e

DSSD sensors

- Double-sided Si strip detectors
- Provide 2-D spatial information
- Depletion voltage 20-60 V,
 Operation voltage 100 V readout AI





- 3 different DSSD shapes
 - \circ ~~ 172 sensors with 1.2 m^2 sensor area
 - 224k readout strips



All sensors have one intermediate floating strip between two readout strips

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Belle II SVD

TIPP2023

SVD layout

- 4 layer structure
- Each layer is organized in mechanically and electrically independent subsets called ladders
- Low material budget: $0.7\% X_0$ per layer
- Diamond sensors for radiation monitor and beam abort

Layer	Ladders	Sensors /ladder	Radius (mm)
L3	7	2	39
L4	10	3	80
L5	12	4	104
L6	16	5	135
Total	45	172	



Front-end ASIC: APV25

- Originally developed for CMS silicon tracker
- Fast: 50 ns shaping times
- Radiation hard: > 100 Mrad
- Power consumption: 0.4 W/chip (700 W in total)
- 128 channels per chip, analog pipeline
- Operated in multi-peak mode @ 32 MHz:
 - 6 subsequent samples recorded

APV25 chips in ladder



Analog signal



3/6-mixed acquisition mode is also prepared for high luminosity runs:

- To reduce background occupancy, dead-time and data-size
- Switching sampling number according to the timing precision of trigger
- The mode is implemented and tested in the real setup

SVD operation & performance

Operational experience

Smooth and reliable operation since the start of data taking

- Efficient shifter/operator/coordinator (local and remote) system
- So far total fraction of masked strips is less than 1%
- One APV25 chip disabled in spring 2019 (out of 1748) and fixed by cable reconnection in summer 2019

Excellent detector performance!

- Cluster charge distribution matches the expectation & very good signal to noise ratio (SNR) → next <u>slide</u>
- Stable hit efficiency: >99% in most of the sensors



- Mar 2019: First collision data
- July 2022: LS1 for maintenance & improvement of machine and detector: installation of the VXD with a new PXD2 completed with two layers + current SVD
- Planning for SuperKEKB to resume in **Dec 2023**

Cluster charge & SNR

- Signal charge depends on the incident angle
- Cluster charges are similar in all sensors and matches the expectations from MIP data taking
- u/P side: agrees with expectation considering the uncertainty in calibration
- v/N side: 10-30% signal loss due to large pitch and floating strip

Very good cluster SNR in all 172

→ MPV: 13 - 30 depending on

sensor position and side

inter-strip capacitance

u/P side: Noise is generally larger due to longer strip length and larger



sensors

20

0.3

0.25

0.2

0.15

0.1

0.05

3.x.2 sensors

mu mu events

data: exp24

24 ke-

40

2ke

Entries

Position resolution

- Using the residual of the cluster position with respect to the intercept of the track extrapolation
 - Measured on di-muon sample $(e^+e^- \rightarrow \mu^+\mu^-)$
 - Effect of track extrapolation error is subtracted
- Good resolution achieved; generally in agreement with pitch expectations
- Good stability during operation





$$\sigma_{x} = \sqrt{\left\langle (\Delta x_{i})^{2} - (\sigma_{x,i}^{\text{trk}})^{2} \right\rangle}$$

$$\sigma_{x,i}^{\text{trk}} = \text{unbiased track position error}$$

Hit time resolution

- Excellent hit time resolution (< 3 ns)
 - Measured w.r.t. event time of the collision provided by Central Drift Chamber (CDC)

- **Track time** computed combining hit time of clusters associated to the track:
 - relative to the time of the collision
- Event time computed combining hit time of clusters associated to all tracks of the event
 - Same resolution (~ 1 ns) and 2000 times faster computation time w.r.t. the one computed with CDC
 - Allowing to speed up the High Level Trigger reconstruction and therefore cope with the higher trigger rate expected at high luminosity



The power of hit time

- Physics signal hits come from triggered collision, while off-time beam background hits come from many other bunches
 - SuperKEKB has continuous bunch crossing (bunch spacing 6 ns)
 - SVD sees hits from machine beam induced background from several bunches near the triggered collision (O(100 ns))
- A selection based on SVD hit-time allows to reject off-time beam background hits

physics

Triggered collision

Belle II SVD



bunch

 ρ^{-}

background

Beam background, radiation effects & future perspective

Beam Background effects

- 1. Integrated radiation damage → can deteriorate sensor performance increasing leakage current, strip noise & changing depletion voltage
 - \circ Dose and sensor parameters constantly monitored to assess the effect over the experiment lifetime \rightarrow good safety margin
- 2. High instantaneous SVD hit occupancy \rightarrow can degrade tracking performance
 - Present average hit occupancy in layer 3 is less than 0.5% and well under control
 - Developments in SVD reconstruction SW to improve robustness against future higher occupancy
- Background extrapolation at nominal luminosity of L = 6 x 10³⁵ cm⁻² s⁻¹ estimated with detailed simulation of different sources (scaling MC with data/MC ratio).
 - Average occupancy of about 4.7 % in layer-3.
 - TID ~ 0.35 Mrad/yr , eq neutron fluence ~ $8 \times 10^{11} n_{eq}$ /cm²/yr
- CAVEAT: Large uncertainty on long term background extrapolation linked to future machine evolution and possible interaction region re-design, currently under study
 - Different BG scenarios (nominal, conservative) studied to assess SVD occupancy limits to preserve good tracking performance



Belle II SVD

Integrated dose

- Diamond sensors used to monitor radiation dose
 - Correlation between SVD occupancy and diamond dose is used to estimate the SVD sensor dose
- Total SVD integrated dose on layer 3 mid plane < 70 krad
 - 1-MeV equivalent neutron fluence evaluated to be
 - ~1.6 × 10¹¹ n_{eq}/cm^2 in first 3 years
 - Assume n_{eq} /dose fluence ratio = 2.3 × 10⁹ n_{eq}/cm^2 /krad from simulation

• First observable effects on sensor currents, noise and calibration constants, but **so far without degradation of the SVD performance**



Integrated dose in SVD Layers

Radiation effects (1)

Strip noise

- Noise increase is < 20% (30%) for n(p) side, not affecting performance
- Non-linear increase due to fixed oxide charges in irradiated sensors → expected to saturate

Leakage current

- Good linear correlation between leakage current and dose (equivalent neutron fluence) as expected from NIEL model
- Irradiation is not expected to degrade SVD performance, even up to 6 Mrad:
 - Contribution to noise negligible now due to short APV25 shaping time
 - After 6 Mrad SNR expected to be < 10 in Layer 3, due to the increased strip noise from leakage current contribution

Noise average [e⁻]

 Good safety margin of about 2 on integrated radiation effects, considering background levels extrapolation at nominal luminosity: ~ 0.35 Mrad/yr & 8x10¹¹ n_{ed}/cm²/yr



Radiation effects (2)

Depletion voltage

- Bulk damage can change effective doping and depletion voltage
 - Measure depletion voltage with scan (n-side strip noise vs bias voltage)
 - No change in full depletion voltage observed with time so far, consistent with low integrated neutron fluence



L3.1.2 N Side - Noise





Irradiation campaign in July 2022

- 90 MeV e⁻ beam @ ELPH Sendai (Tohoku Univ.)
- Type inversion confirmed ~2 Mrad \rightarrow a equivalent neutron fluence ~6 × 10¹² $n_{_{ed}}/cm^2$
- Expect SVD sensor to work well also above type inversion:
 - Experience on BaBar sensor [NIMA 729, 615-701, 2013]
 - New measurements with Sr90 source on type inverted SVD ladder

SVD hit-time selections

• Challenge for the near future

- Improving SVD software robustness against high-background data expected with increasing luminosity
- In high-background conditions, the fake rate will increase, degrading the SVD tracking performance
- Excellent SVD hit-time performance (resolution < 3 ns) allows to exploit SVD hit-time to efficiently remove off-time background
 - Efficient to remove 50% off-time hit background, keeping signal efficiency above 99%
 - Background rejection based on SVD hit-time selections already tested but not yet deployed on real data reconstruction

→ Fake rate: tracks reconstructed with hits from beam-induced background or originating from wrong combinations of hits

SVD hit time distribution (data May 2022)



• SVD hit-time selections allow to set the SVD occupancy limit at 4.7% in nominal background scenario (in the conservative scenario, SVD occupancy ~7.2% → we start to see some SVD tracking degradation)

 $|t_{u,v}| < 50 \text{ ns}$ $|t_u - t_v| < 20 \text{ ns}$

Throw the heart over the obstacle

- Further decrease of fake rate will come from SVD cluster-time grouping and selection based on track time
- Cluster Grouping
 - Exploit SVD hit-time to implement a event-by-event classification of groups of hits (clusters)
 - Selection based on Grouping further reduces the fake rate by 15% on high-background data
- Selection on track-time to remove off-time tracks
 - Further reduce the fake rate by a factor 1.5 on high-background data
- New features allow to further increase SVD occupancy limit from 4.7% to ~6%
- Possible re-design of the interaction region & small safety factor, due to large uncertainty on expected background, motivate the vertex detector upgrade now under study to improve tolerance to hit rates & radiation → technology assessment ongoing



VXD reinstallation during LS1

VXD reinstallation

- The second layer of PXD covers only one-sixth of the azimuthal angle
 - Upgrade VXD with new complete PXD + current SVD during LS1
 - Intense hardware activities on the SVD for the VXD de-installation/re-installation
 - Procedure for SVD detachment was well developed and reviewed in advance
 - SVD detachment & reattachment were done successfully
 - Sanity check with local runs shows no issues during the procedure







Belle II SVE

VXD now re-installed in Belle II \rightarrow commissioning with cosmics in September



Summary & conclusions

- SVD has been taking data since March 2019 smoothly and reliably
- Excellent performance in agreement with expectations
- Observed first effects of radiation damage, not affecting performance
- Improving SVD software robustness against future high background
- During Long Shutdown we installed the new VXD, with the complete PXD2 and the current SVD
 - VXD re-commissioning with cosmic in Sep
 - On track to resume beam operation in Dec 2023
- SVD technical paper has been published in JINST :

The design, construction, operation and performance of the Belle II silicon vertex detector

Thank you for your attention!

Additional slides

Origami chip on sensor concept

- Readout chips directly on each middle sensor:
 - APV chips thinned to 100 um to reduce material budget
 - \circ Shorter signal propagation length \rightarrow smaller capacitance and noise
- Wrapped flex to read both sides from the same side
- Cool only one side with bi-phase $-20 \degree C CO_2$







Belle II SVD

Construction, assembly and installation



- Sep 2008: First chip-on-sensor origami concept
- Oct 2010: Belle II Technical Design Report
- May 2015: First completed L5 ladder
- Feb/Jul 2018: First/second SVD half shell assembled
- Nov 2018: Installed in Belle II
- Mar 2019: First collision data with complete detector
- July 2022: LS1





Hit efficiency

Average Efficiency per layer

Shown for **Feb-June**, **2022**

Very high and stable in time

time > 99 % for most of the



sensors



Vertex resolution

Excellent vertex resolution!

F Measured d0 resolution of 14.1 ± 0.1 μm

- D lifetime measurement
 - Vertex determination plays a key role in the lifetime measurement
 - Belle II time resolution is better than Belle/BaBar by factor about 2
 - World's most precise D lifetime measurements!

